

**Search Notes**

Application/Control No.

10/659,276

Examiner

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Applicant(s)/Patent under  
Reexamination

NAKANISHI, YUTAKA

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner
348	373- 376,333	11/15/2006	TL
D16	all	11/16/2006	TL
386	117-118-1	11/17/2006	TL
348	211.2	3/28/2007	TL
360	85,93	3/28/2007	TL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	11/15/2006	TL
US-PGPUB,USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	11/15/2006	TL
INSPEC (same search key as in EAST)	11/15/2006	TL